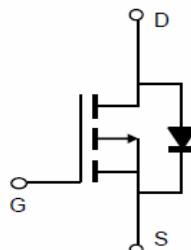


### • Product Summary

Part #	V <sub>DS</sub>	R <sub>DS(on).typ</sub> (@V <sub>GS</sub> =10V)	R <sub>DS(on).typ</sub> (@V <sub>GS</sub> =4.5V)	I <sub>D</sub>
EFM4485	-40V	12mΩ	16mΩ	-12A

### • Description

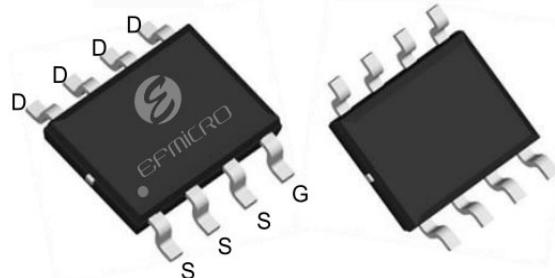
- The EFM4485 is the high cell density trenched
- N-ch MOSFETs which provide excellent
- RDSON and gate charge for most of the
- synchronous buck converter applications.
- The EFM4485 meet the RoHS and Green
- Product requirement, 100 % EAS guaranteed
- with full function reliability approved.



P-Channel MOSFET

### • Application

- Super Low Gate Charge 100% EAS Guaranteed
- Green Device Available Excellent CdV/dt effect decline
- Advanced high cell density Trench technology



SOP-8

### • Ordering Information:

Part NO.	EFM4485
Marking	4485 *****
Packing Information	REEL TAPE
Basic ordering unit (pcs)	3000

### • Absolute Maximum Ratings (T<sub>C</sub>=25°C)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	-40	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current-Continuous	I <sub>D</sub>	-12	A
Drain Current-Pulsed <sup>(Note 1)</sup>	I <sub>DM</sub>	52	A
Maximum Power Dissipation	P <sub>D</sub>	3.1	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 To 150	°C

### • Thermal Characteristic

Thermal Resistance, Junction-to-Ambient <sup>(Note 2)</sup>	R <sub>θJA</sub>	41	°C/W
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**• Static Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise stated)**

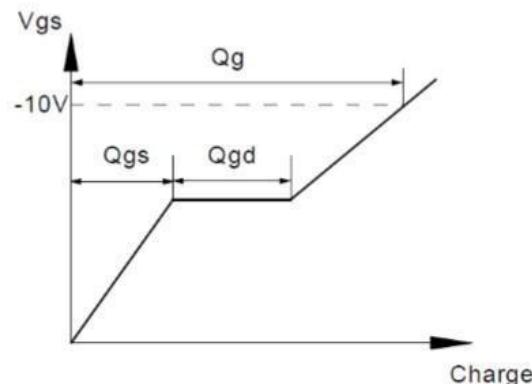
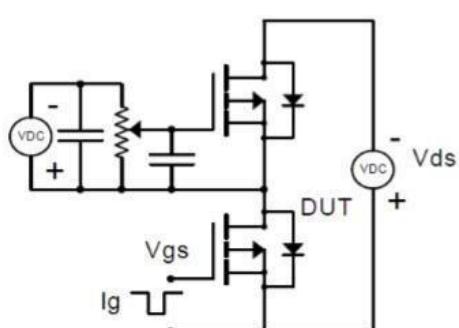
Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V} I_{\text{D}}=250\mu\text{A}$	-40	--	--	V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}}=-40\text{V} V_{\text{GS}}=0\text{V}$	--	--	-1	$\mu\text{A}$
Gate-Body Leakage Current	$I_{\text{GSS}}$	$V_{\text{GS}}=\pm 20\text{V} V_{\text{DS}}=0\text{V}$	--	--	$\pm 100$	nA
<b>On Characteristics</b> <small>(Note 3)</small>						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{DS}}=V_{\text{GS}} I_{\text{D}}=250\mu\text{A}$	-1.0	-1.6	-2.2	V
Drain-Source On-State Resistance	$R_{\text{DS(ON)}}$	$V_{\text{GS}}=-10\text{V} I_{\text{D}}=-10\text{A}$	--	12	15	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V} I_{\text{D}}=-8\text{A}$	--	16	20	$\text{m}\Omega$
Forward Transconductance	$g_{\text{FS}}$	$V_{\text{DS}}=-5\text{V} I_{\text{D}}=-10\text{A}$	--	25	--	S
Gate Resistance	$R_g$	$F=1.0\text{MHz}$	--	4	--	$\Omega$
<b>Dynamic Characteristics</b> <small>(Note 4)</small>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}}=-20\text{V} V_{\text{GS}}=0\text{V}$ $F=1.0\text{MHz}$	--	2500	--	PF
Output Capacitance	$C_{\text{oss}}$		--	260	--	PF
Reverse Transfer Capacitance	$C_{\text{rss}}$		--	180	--	PF
<b>Switching Characteristics</b> <small>(Note 4)</small>						
Turn-on Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}}=-20\text{V} I_{\text{D}}=-10\text{A}$ $V_{\text{GS}}=-10\text{V} R_{\text{G}}=3\Omega$	--	9.4	--	nS
Turn-on Rise Time	$t_r$		--	20	--	nS
Turn-Off Delay Time	$t_{\text{d(off)}}$		--	55	--	nS
Turn-Off Fall Time	$t_f$		--	30	--	nS
Total Gate Charge	$Q_g$	$V_{\text{DS}}=-20\text{V} I_{\text{D}}=-10\text{A}$ $V_{\text{GS}}=-10\text{V}$	--	42	--	nC
Gate-Source Charge	$Q_{\text{gs}}$		--	7	--	nC
Gate-Drain Charge	$Q_{\text{gd}}$		--	8.6	--	nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage <small>(Note 3)</small>	$V_{\text{SD}}$	$V_{\text{GS}}=0\text{V} I_{\text{S}}=-10\text{A}$	--	-0.8	-1.2	V
Diode Forward Current <small>(Note 2)</small>	$I_{\text{S}}$		--	--	-12	A

Note :

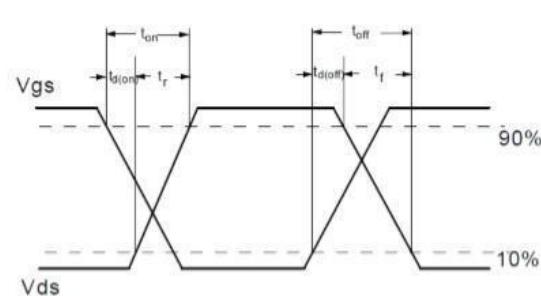
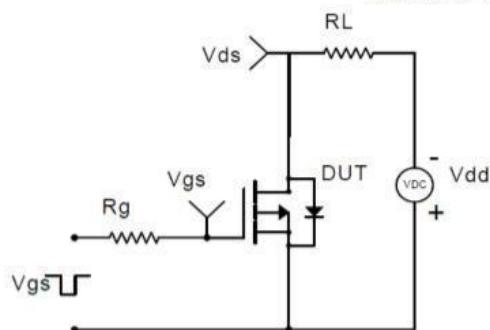
1. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .
2. The EAS data shows Max. rating . The test condition is  $V_{\text{DD}}= -25\text{V}$ ,  $V_{\text{GS}}= -10\text{V}$ ,  $L= 0.1\text{mH}$ ,  $I_{\text{AS}}= -34\text{A}$ .
3. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width  $\leq 300\text{us}$  , duty cycle  $\leq 2\%$ .
5. This value is guaranteed by design hence it is not included in the production test.

## • Test Circuit

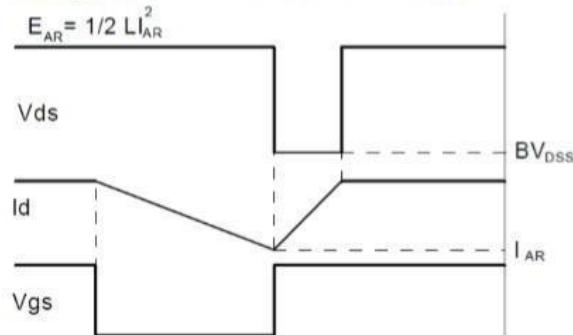
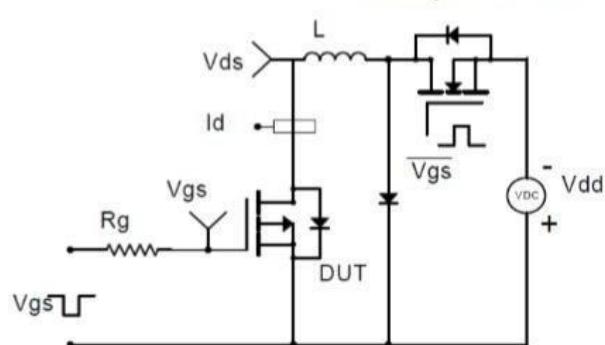
Gate Charge Test Circuit &amp; Waveform



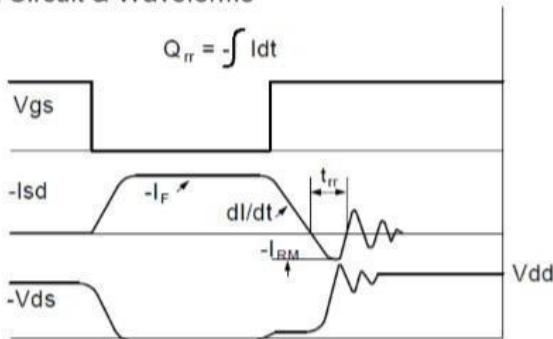
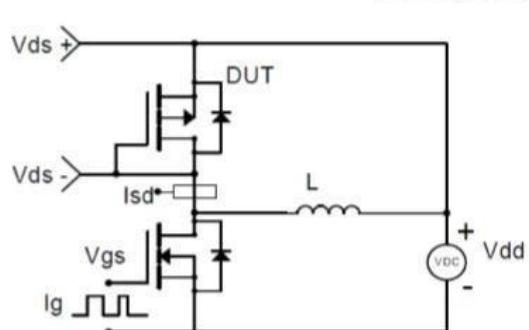
Resistive Switching Test Circuit &amp; Waveforms



Unclamped Inductive Switching (UIS) Test Circuit &amp; Waveforms



Diode Recovery Test Circuit &amp; Waveforms



## • Typical Characteristics

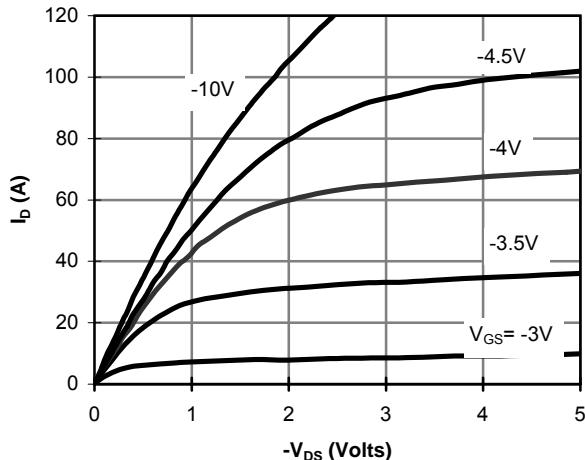


Figure 1: On-Region Characteristics

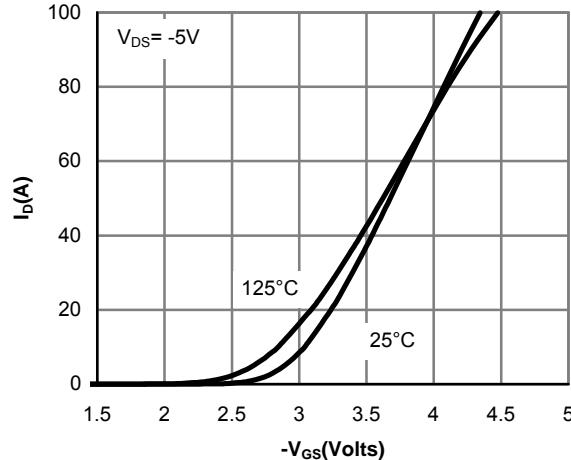


Figure 2: Transfer Characteristics

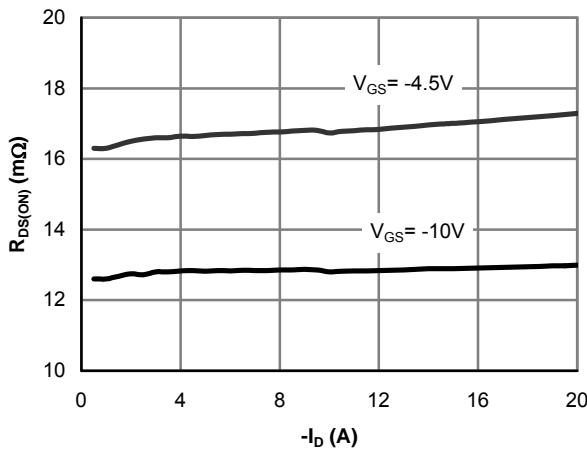


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

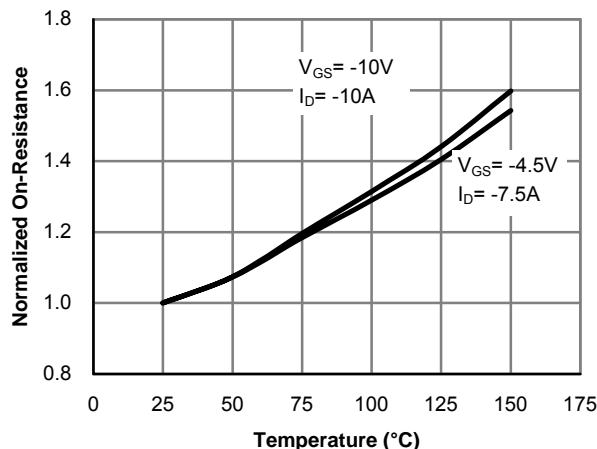


Figure 4: On-Resistance vs. Junction Temperature

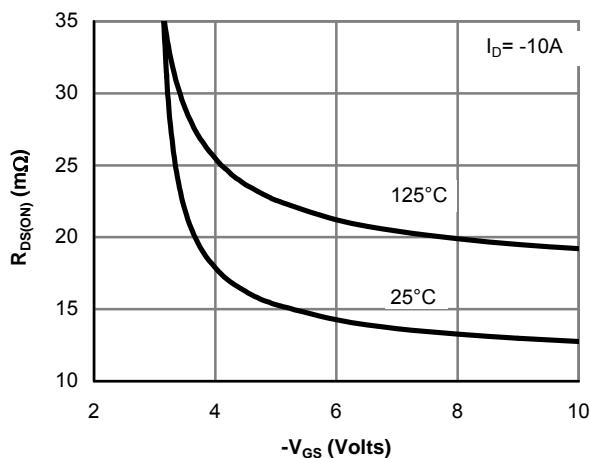


Figure 5: On-Resistance vs. Gate-Source Voltage

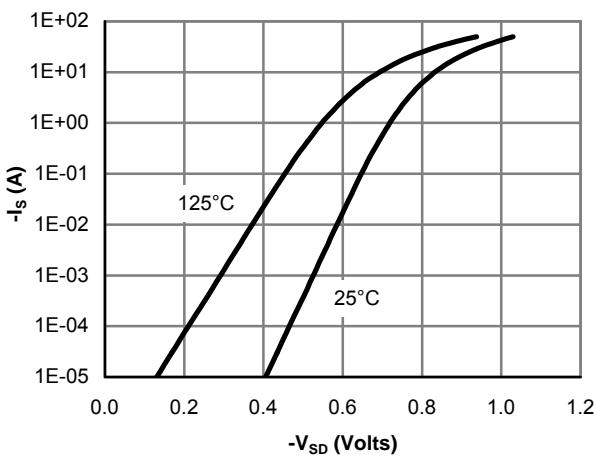


Figure 6: Body-Diode Characteristics

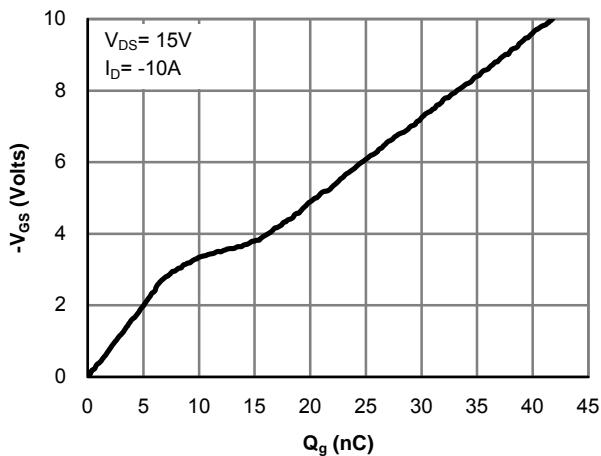


Figure 7: Gate-Charge Characteristics

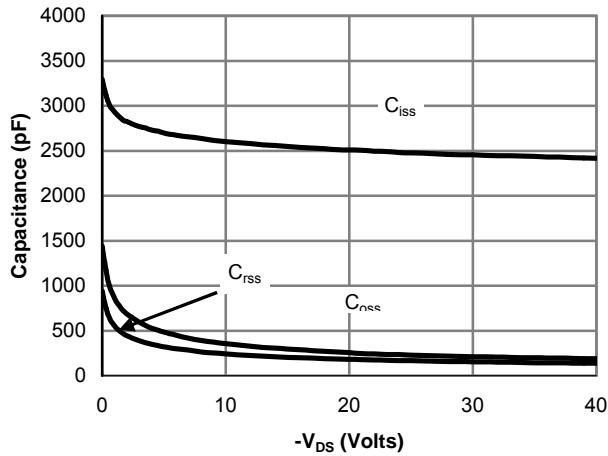
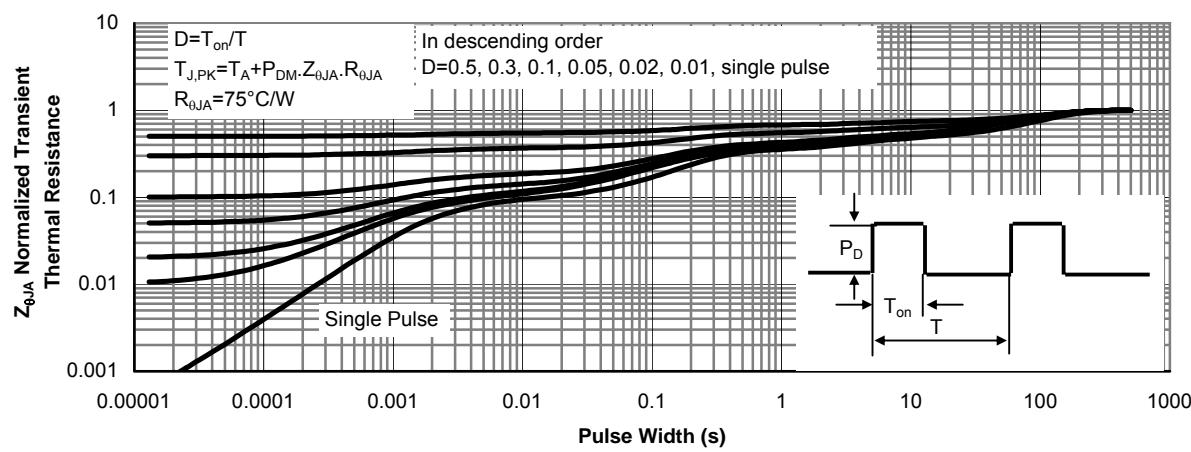
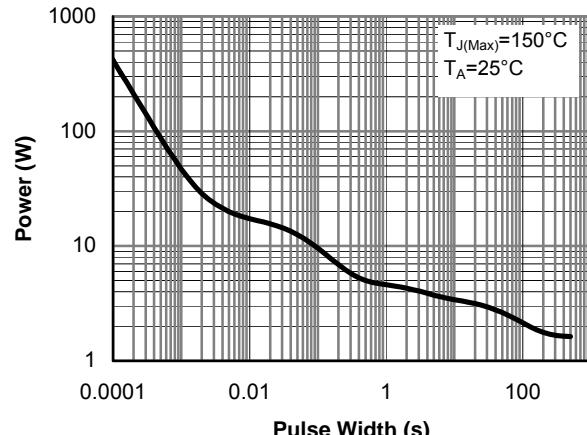
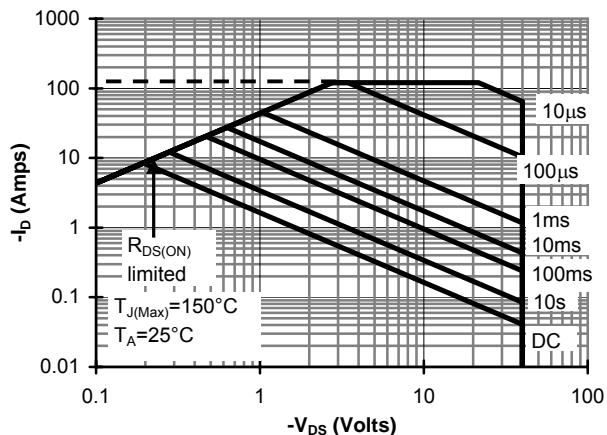
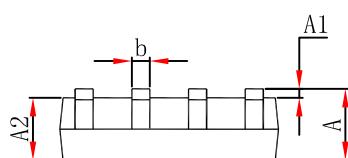
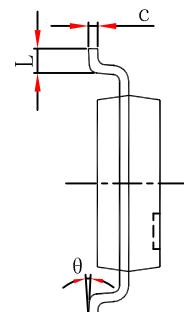
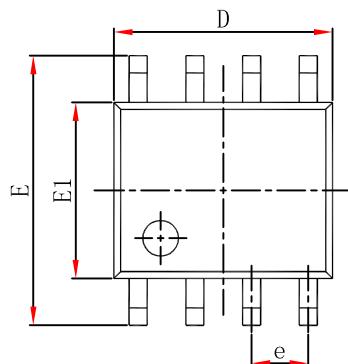
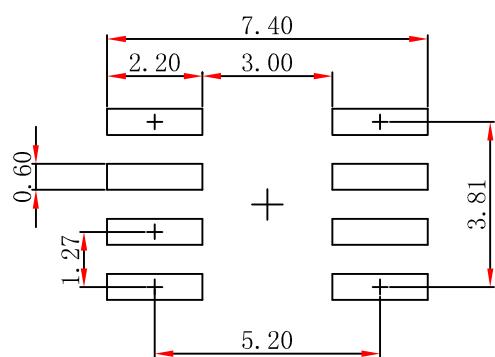


Figure 8: Capacitance Characteristics



**SOP8 Package Outline Dimensions**


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.450	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.007	0.010
D	4.700	5.100	0.185	0.201
e	1.270 (BSC)		0.050 (BSC)	
E	5.800	6.200	0.228	0.244
E1	3.800	4.000	0.150	0.157
L	0.400	1.270	0.016	0.050
$\theta$	0°		8°	


**Note:**

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.05$ mm.
3. The pad layout is for reference purposes only.